TPS22918 5.5V、2A、导通电阻为 52mΩ 的负载开关

1 特性

- 集成单通道负载开关
- 环境工作温度范围：-40°C 至 +105°C
- 输入电压范围：1V 至 5.5V
- 导通电阻 (R_{ON})
  - R_{ON} = 52mΩ（V_{IN} = 5V 时的典型值）
  - R_{ON} = 53mΩ（V_{IN} = 3.3V 时的典型值）
- 2A 最大持续开关电流
- 低静态电流
  - 8.3μA（V_{IN} = 3.3V 时的典型值）
- 低控制输入阈值，允许使用 1V 或电压更高的 GPIO
- 可调节快速输出放电 (QOD)
- 可通过 CT 引脚配置的上升时间
- 小外形尺寸晶体管 (SOT-23)-6 封装 (DBV)
  - 2.90mm × 2.80mm，间距为 0.95mm，高度为 1.45mm（带引线）
- 静电放电 (ESD) 性能经测试符合 JESD 22 规范
  - ±2kV 人体模型 (HBM) 和 ±1kV 带电器件模型 (CDM)

2 应用

- 工业系统
- 机顶盒
- 血糖仪
- 电子销售终端

3 说明

TPS22918 是一款单通道负载开关，可对上升时间和快速输出放电进行配置。此器件包括一个 N 沟道金属氧化物半导体场效应晶体管 (MOSFET)，可在 1V 至 5.5V 的输入电压范围内运行并可支持 2A 的最大持续电流。此开关由一个开关输入控制，能够直接连接低电压控制信号。

该器件的可配置上升时间可大幅降低大容量负载电容所产生的浪涌电流，从而降低或消除电源压降。TPS22918 具有 一个可配置的快速输出放电 (QOD) 引脚，用于控制器件的下降时间，以便针对掉电或排序进行灵活设计。

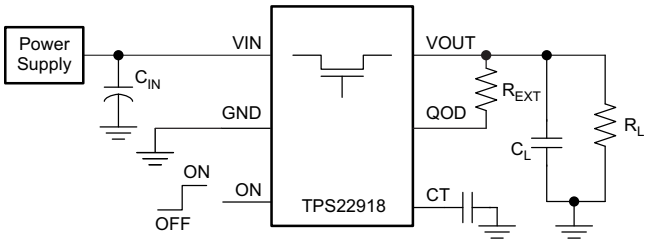
TPS22918 采用小型、带引线的 SOT-23 封装 (DBV)，方便对焊接点进行外观检查。该器件在自然通风环境下的额定运行温度范围为 –40°C 至 +105°C。

器件信息 (1)

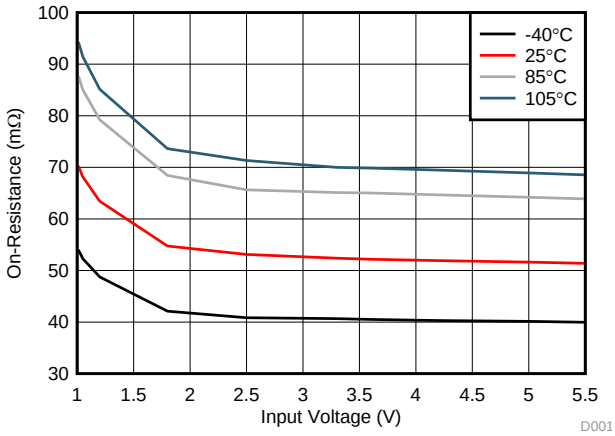
部件号	封装	封装尺寸（标称值）
TPS22918	SOT-23 (6)	2.90mm x 1.60mm

(1) 如需了解所有可用封装，请见数据表末尾的可订购产品附录。

简化电路原理图



R_{ON} 与 V_{IN} 间的关系 (I_{OUT} = –200mA)
典型值



An IMPORTANT NOTICE at the end of this data sheet addresses availability, warranty, changes, use in safety-critical applications, intellectual property matters and other important disclaimers. PRODUCTION DATA.

目录

1 特性 ... 1
2 应用 ... 1
3 说明 ... 1
4 修订历史记录 ... 2
5 **Pin Configuration and Functions** ... 3
6 **Specifications** ... 4
6.1 Absolute Maximum Ratings ... 4
6.2 ESD Ratings ... 4
6.3 Recommended Operating Conditions ... 4
6.4 Thermal Information ... 4
6.5 Electrical Characteristics ... 5
6.6 Switching Characteristics ... 6
6.7 Typical Characteristics ... 7
7 **Parameter Measurement Information** ... 11
8 **Detailed Description** ... 12
8.1 Overview ... 12
8.2 Functional Block Diagram ... 12
8.3 Feature Description ... 13
8.4 Device Functional Modes ... 15
9 **Application and Implementation** ... 16
9.1 Application Information ... 16
9.2 Typical Application ... 16
10 **Power Supply Recommendations** ... 20
11 **Layout** ... 20
11.1 Layout Guidelines ... 20
11.2 Layout Example ... 21
11.3 Thermal Considerations ... 21
12 器件和文档支持 ... 22
12.1 器件支持 ... 22
12.2 文档支持 ... 22
12.3 社区资源 ... 22
12.4 商标 ... 22
12.5 静电放电警告 ... 22
12.6 Glossary ... 22
13 机械、封装和可订购信息 ... 22

4 修订历史记录

注：之前版本的页码可能与当前版本有所不同。

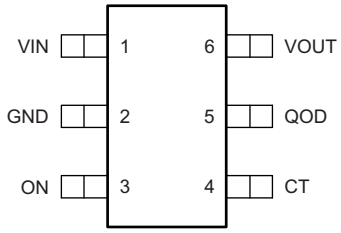
Changes from Original (February 2016) to Revision A **Page**

- 已将器件状态由“*产品预览*”更改为“*量产数据*” ... 1

Copyright © 2016, Texas Instruments Incorporated

5 Pin Configuration and Functions

DBV Package
6-Pin SOT-23
Top View



Pin Functions

PIN		I/O	DESCRIPTION
NO.	NAME		
1	VIN	I	Switch input. Place ceramic bypass capacitor(s) between this pin and GND. See the *Detailed Description* section for more information.
2	GND	—	Device ground.
3	ON	I	Active high switch control input. Do not leave floating.
4	CT	O	Switch slew rate control. Can be left floating. See the *Feature Description* section for more information.
5	QOD	O	Quick Output Discharge pin. This functionality can be enabled in one of three ways. • Placing an external resistor between VOUT and QOD • Tying QOD directly to VOUT and using the internal resistor value (R_{PD}) • Disabling QOD by leaving pin floating See the *Quick Output Discharge (QOD)* section for more information.
6	VOUT	O	Switch output.

Copyright © 2016, Texas Instruments Incorporated

6 Specifications

6.1 Absolute Maximum Ratings

Over operating free-air temperature range (unless otherwise noted) (1) (2)

		MIN	MAX	UNIT
V_{IN}	Input voltage	–0.3	6	V
V_{OUT}	Output voltage	–0.3	6	V
V_{ON}	ON voltage	–0.3	6	V
I_{MAX}	Maximum continuous switch current, ambient temperature = 70°C		2	A
I_{PLS}	Maximum pulsed switch current, pulse < 300 µs, 2% duty cycle		2.5	A
T_J	Maximum junction temperature		125	°C
T_{stg}	Storage temperature	–65	150	°C

(1) Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under *Recommended Operating Conditions*. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
(2) All voltage values are with respect to network ground terminal.

6.2 ESD Ratings

			VALUE	UNIT
$V_{(ESD)}$	Electrostatic discharge	Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001 (1)	±2000	V
		Charged-device model (CDM), per JEDEC specification JESD22-C101 (2)	±1000	

(1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.
(2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

6.3 Recommended Operating Conditions

Over operating free-air temperature range (unless otherwise noted)

			MIN	MAX	UNIT
V_{IN}	Input voltage		0	5.5	V
V_{ON}	ON voltage		0	5.5	V
V_{OUT}	Output voltage			V_{IN}	V
$V_{IH, ON}$	High-level input voltage, ON	V_{IN} = 1 V to 5.5 V	1	5.5	V
$V_{IL, ON}$	Low-level input voltage, ON	V_{IN} = 1 V to 5.5 V	0	0.5	V
T_A	Operating free-air temperature range (1)		–40	105	°C
C_{IN}	Input Capacitor		1 (2)		µF

(1) In applications where high power dissipation and/or poor package thermal resistance is present, the maximum ambient temperature may have to be derated. Maximum ambient temperature [$T_{A(max)}$] is dependent on the maximum operating junction temperature [$T_{J(MAX)}$], the maximum power dissipation of the device in the application [$P_{D(MAX)}$], and the junction-to-ambient thermal resistance of the part/package in the application (θ_{JA}), as given by the following equation: $T_{A(MAX)} = T_{J(MAX)} - (\theta_{JA} \times P_{D(MAX)})$.
(2) Refer to *Application and Implementation* section

6.4 Thermal Information

THERMAL METRIC (1)		TPS22918 DBV (SOT-23) 6 PINS	UNIT
$R_{\theta JA}$	Junction-to-ambient thermal resistance	183.2	°C/W
$R_{\theta JC(top)}$	Junction-to-case (top) thermal resistance	151.6	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	34.1	°C/W
ψ_{JT}	Junction-to-top characterization parameter	37.2	°C/W
ψ_{JB}	Junction-to-board characterization parameter	33.6	°C/W

(1) For more information about traditional and new thermal metrics, see the *Semiconductor and IC Package Thermal Metrics* application report, SPRA953.

Copyright © 2016, Texas Instruments Incorporated

6.5 Electrical Characteristics

Unless otherwise noted, the specification in the following table applies over the full ambient operating temperature –40°C ≤ T_A ≤ +105°C. Typical values are for T_A = 25°C.

PARAMETER		TEST CONDITIONS		T_A	MIN	TYP	MAX	UNIT
$I_{Q, VIN}$	Quiescent current	V_{ON} = 5 V, I_{OUT} = 0 A	V_{IN} = 5.5 V	–40°C to +105°C		9.2	16	µA
			V_{IN} = 5 V			8.7	16	
			V_{IN} = 3.3 V			8.3	15	
			V_{IN} = 1.8 V			10.2	17	
			V_{IN} = 1.2 V			9.3	16	
			V_{IN} = 1 V			8.9	15	
$I_{SD, VIN}$	Shutdown current	V_{ON} = 0 V, V_{OUT} = 0 V	V_{IN} = 5.5 V	–40°C to +105°C		0.5	5	µA
			V_{IN} = 5 V			0.5	4.5	
			V_{IN} = 3.3 V			0.5	3.5	
			V_{IN} = 1.8 V			0.5	2.5	
			V_{IN} = 1.2 V			0.4	2	
			V_{IN} = 1 V			0.4	2	
I_{ON}	ON pin input leakage current	V_{IN} = 5.5 V, I_{OUT} = 0 A		–40°C to +105°C			0.1	µA
R_{ON}	On-Resistance	V_{IN} = 5.5 V, I_{OUT} = –200 mA		25°C		51	59	mΩ
				–40°C to +85°C			71	
				–40°C to +105°C			78	
		V_{IN} = 5.0 V, I_{OUT} = –200 mA		25°C		52	59	mΩ
				–40°C to +85°C			71	
				–40°C to +105°C			79	
		V_{IN} = 4.2 V, I_{OUT} = –200 mA		25°C		52	59	mΩ
				–40°C to +85°C			71	
				–40°C to +105°C			79	
		V_{IN} = 3.3 V, I_{OUT} = –200 mA		25°C		53	59	mΩ
				–40°C to +85°C			71	
				–40°C to +105°C			80	
		V_{IN} = 2.5 V, I_{OUT} = –200 mA		25°C		53	61	mΩ
				–40°C to +85°C			75	
				–40°C to +105°C			80	
		V_{IN} = 1.8 V, I_{OUT} = –200 mA		25°C		55	65	mΩ
				–40°C to +85°C			79	
				–40°C to +105°C			88	
		V_{IN} = 1.2 V, I_{OUT} = –200 mA		25°C		64	77	mΩ
				–40°C to +85°C			88	
				–40°C to +105°C			104	
		V_{IN} = 1.0 V, I_{OUT} = –200 mA		25°C		71	85	mΩ
				–40°C to +85°C			100	
				–40°C to +105°C			116	
V_{HYS}	ON pin hysteresis	V_{IN} = 1 V to 5.5 V		–40°C to +105°C		107		mV
R_{PD}	Output pull down resistance(1)	V_{IN} = 5.0 V, V_{ON} = 0 V		25°C		24		Ω
				–40°C to +105°C			30	
		V_{IN} = 3.3 V, V_{ON} = 0 V		25°C		25		
				–40°C to +105°C			35	
		V_{IN} = 1.8 V, V_{ON} = 0 V		25°C		45		
				–40°C to +105°C			60	

(1) Output pull down resistance varies with input voltage. Please see Figure 7 for more information.

Copyright © 2016, Texas Instruments Incorporated

6.6 Switching Characteristics

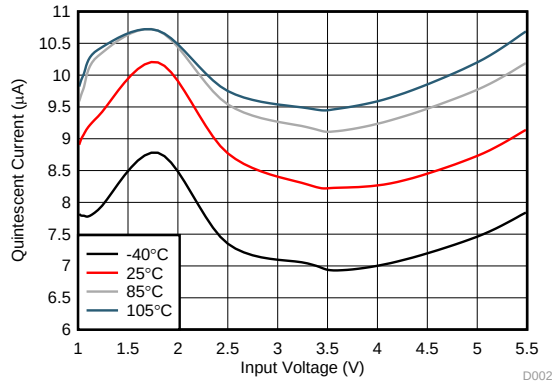
Refer to the timing test circuit in Figure 21 (unless otherwise noted) for references to external components used for the test condition in the switching characteristics table. Switching characteristics shown below are only valid for the power-up sequence where V_{IN} is already in steady state condition before the ON pin is asserted high. V_{ON} = 5 V, T_A = 25 °C, QOD = Open.

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
V_{IN} = 5 V						
t_{ON}	Turn-on time	R_L = 10 Ω, C_{IN} = 1 µF, C_L = 0.1 µF, CT = 1000 pF		1950		µs
t_{OFF}	Turn-off time	R_L = 10 Ω, C_{IN} = 1 µF, C_L = 0.1 µF, CT = 1000 pF		2		
t_R	V_{OUT} rise time	R_L = 10 Ω, C_{IN} = 1 µF, C_L = 0.1 µF, CT = 1000 pF		2540		
t_F	V_{OUT} fall time	R_L = 10 Ω, C_{IN} = 1 µF, C_L = 0.1 µF, CT = 1000 pF		2		
t_D	Delay time	R_L = 10 Ω, C_{IN} = 1 µF, C_L = 0.1 µF, CT = 1000 pF		690		
V_{IN} = 3.3 V						
t_{ON}	Turn-on time	R_L = 10 Ω, C_{IN} = 1 µF, C_L = 0.1 µF, CT = 1000 pF		1430		µs
t_{OFF}	Turn-off time	R_L = 10 Ω, C_{IN} = 1 µF, C_L = 0.1 µF, CT = 1000 pF		2		
t_R	V_{OUT} rise time	R_L = 10 Ω, C_{IN} = 1 µF, C_L = 0.1 µF, CT = 1000 pF		1680		
t_F	V_{OUT} fall time	R_L = 10 Ω, C_{IN} = 1 µF, C_L = 0.1 µF, CT = 1000 pF		2		
t_D	Delay time	R_L = 10 Ω, C_{IN} = 1 µF, C_L = 0.1 µF, CT = 1000 pF		590		
V_{IN} = 1.8 V						
t_{ON}	Turn-on time	R_L = 10 Ω, C_{IN} = 1 µF, C_L = 0.1 µF, CT = 1000 pF		965		µs
t_{OFF}	Turn-off time	R_L = 10 Ω, C_{IN} = 1 µF, C_L = 0.1 µF, CT = 1000 pF		2		
t_R	V_{OUT} rise time	R_L = 10 Ω, C_{IN} = 1 µF, C_L = 0.1 µF, CT = 1000 pF		960		
t_F	V_{OUT} fall time	R_L = 10 Ω, C_{IN} = 1 µF, C_L = 0.1 µF, CT = 1000 pF		2		
t_D	Delay time	R_L = 10 Ω, C_{IN} = 1 µF, C_L = 0.1 µF, CT = 1000 pF		480		
V_{IN} = 1 V						
t_{ON}	Turn-on time	R_L = 10 Ω, C_{IN} = 1 µF, C_L = 0.1 µF, CT = 1000 pF		725		µs
t_{OFF}	Turn-off time	R_L = 10 Ω, C_{IN} = 1 µF, C_L = 0.1 µF, CT = 1000 pF		3		
t_R	V_{OUT} rise time	R_L = 10 Ω, C_{IN} = 1 µF, C_L = 0.1 µF, CT = 1000 pF		560		
t_F	V_{OUT} fall time	R_L = 10 Ω, C_{IN} = 1 µF, C_L = 0.1 µF, CT = 1000 pF		2		
t_D	Delay time	R_L = 10 Ω, C_{IN} = 1 µF, C_L = 0.1 µF, CT = 1000 pF		430		

Copyright © 2016, Texas Instruments Incorporated

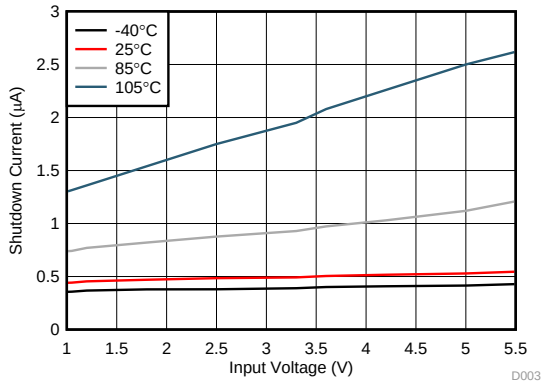
6.7 Typical Characteristics

6.7.1 DC Characteristics



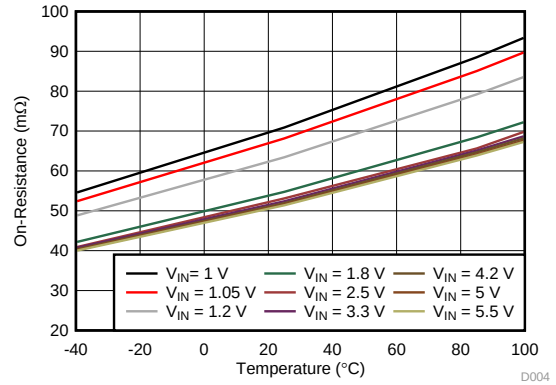
V_{ON} = 5 V I_{OUT} = 0 A

Figure 1. I_Q vs V_{IN}



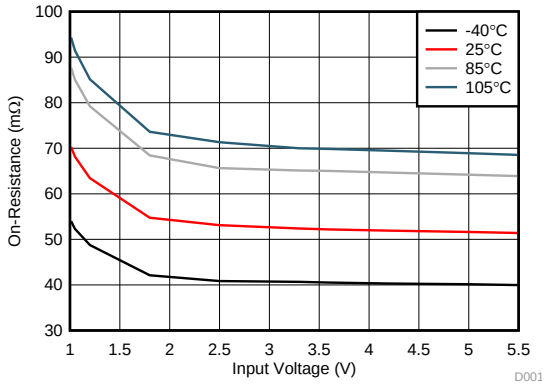
V_{ON} = 0 V I_{OUT} = 0 A

Figure 2. I_{SD} vs V_{IN}



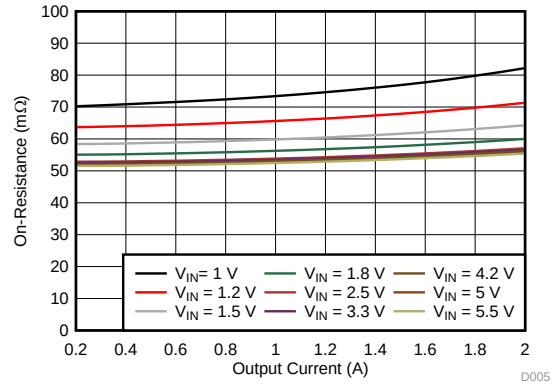
V_{ON} = 5 V I_{OUT} = –200 mA

Figure 3. R_{ON} vs T_J



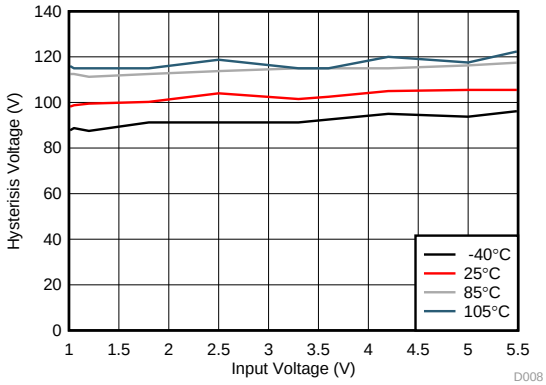
V_{ON} = 5 V I_{OUT} = –200 mA

Figure 4. R_{ON} vs V_{IN}



V_{ON} = 5 V T_A = 25°C

Figure 5. R_{ON} vs I_{OUT}

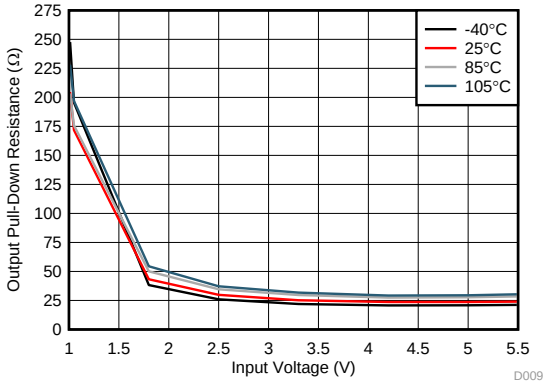


I_{OUT} = 0 A

Figure 6. V_{HYS} vs V_{IN}

Copyright © 2016, Texas Instruments Incorporated

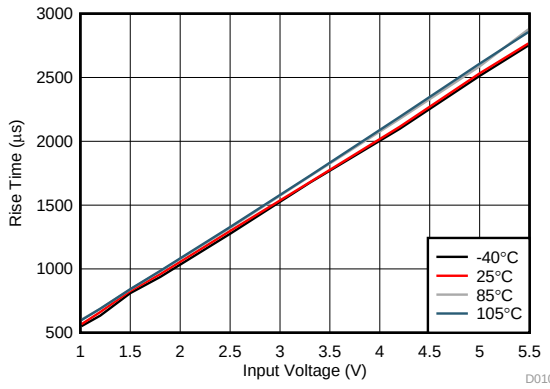
DC Characteristics (continued)



V_{IN} = V_{OUT} V_{ON} = 0 V

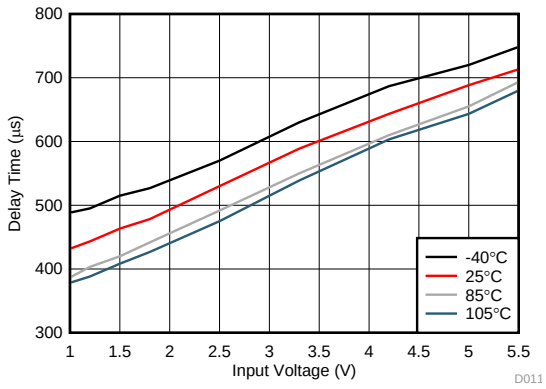
Figure 7. R_{PD} vs V_{IN}

6.7.2 AC Characteristics



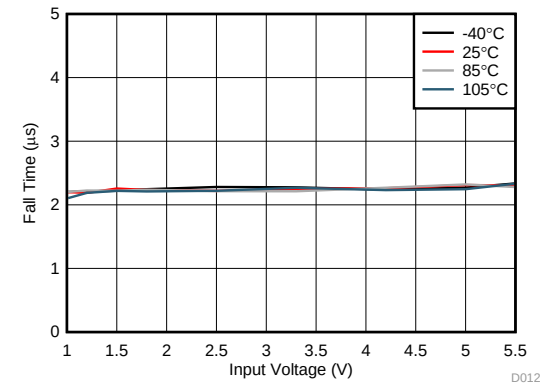
C_{IN} = 1 µF R_L = 10 Ω C_L = 0.1 µF
CT = 1000pF

Figure 8. t_R vs V_{IN}



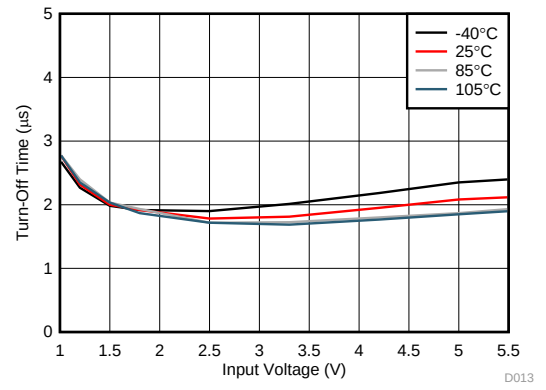
C_{IN} = 1 µF R_L = 10 Ω C_L = 0.1 µF

Figure 9. t_D vs V_{IN}



C_{IN} = 1 µF R_L = 10 Ω C_L = 0.1 µF QOD = Open

Figure 10. t_F vs V_{IN}

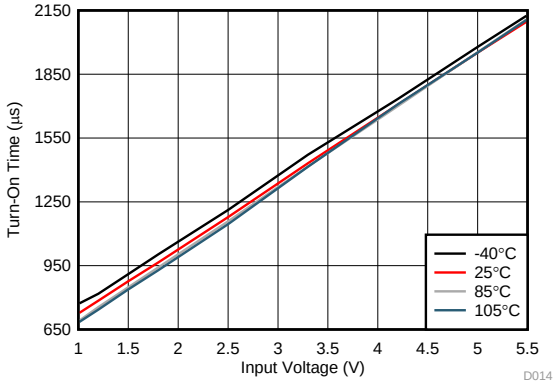


C_{IN} = 1 µF R_L = 10 Ω C_L = 0.1 µF

Figure 11. t_{OFF} vs V_{IN}

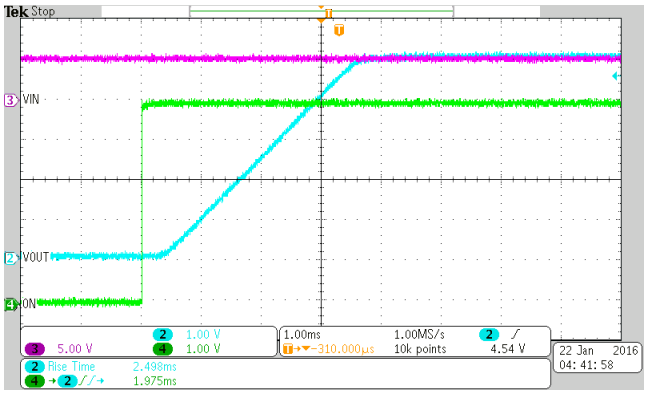
Copyright © 2016, Texas Instruments Incorporated

AC Characteristics (continued)



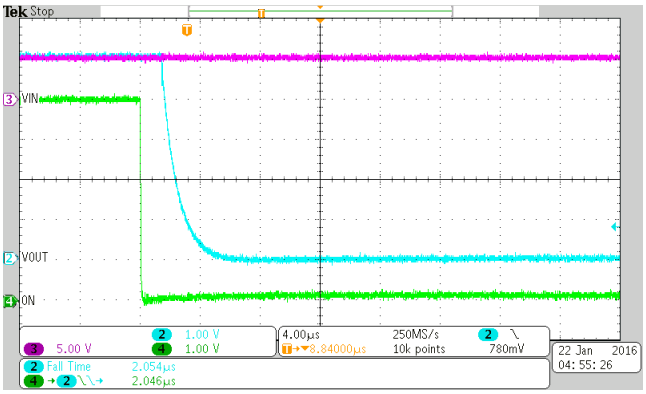
C_{IN} = 1 µF R_L = 10 Ω C_L = 0.1 µF
CT = 1000 pF

Figure 12. t_{ON} vs V_{IN}



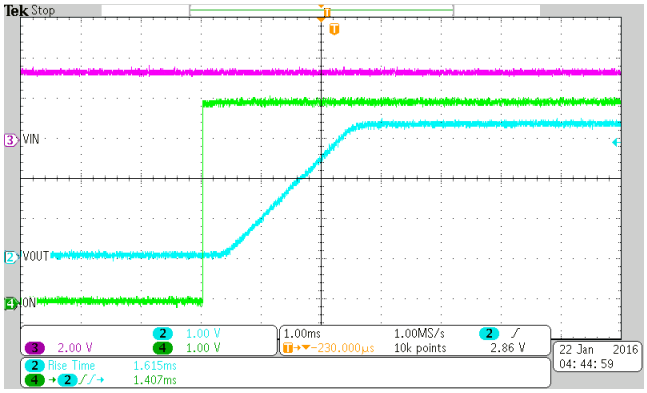
V_{IN} = 5 V C_{IN} = 1 µF C_L = 0.1 µF
R_L = 10 Ω CT = 1000 pF

Figure 13. t_R at V_{IN} = 5 V



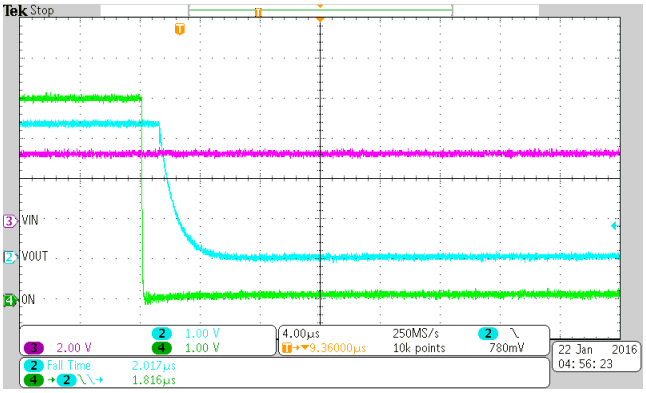
V_{IN} = 5 V C_{IN} = 1 µF C_L = 0.1 µF
R_L = 10 Ω QOD = Open

Figure 14. t_F at V_{IN} = 5 V



V_{IN} = 3.3 V C_{IN} = 1 µF C_L = 0.1 µF
R_L = 10 Ω CT = 1000 pF

Figure 15. t_R at V_{IN} = 3.3 V

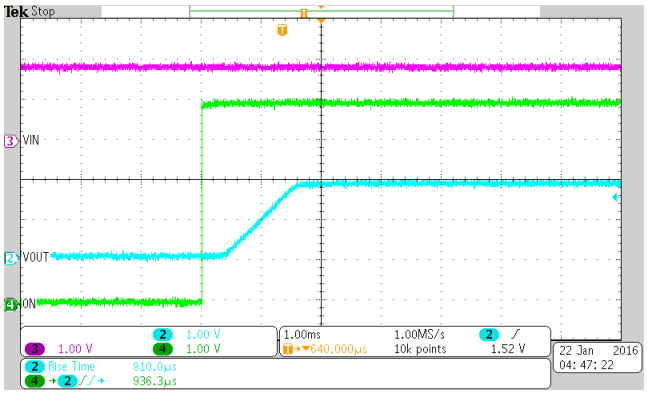


V_{IN} = 3.3 V C_{IN} = 1 µF C_L = 0.1 µF
R_L = 10 Ω QOD = Open

Figure 16. t_F at V_{IN} = 3.3 V

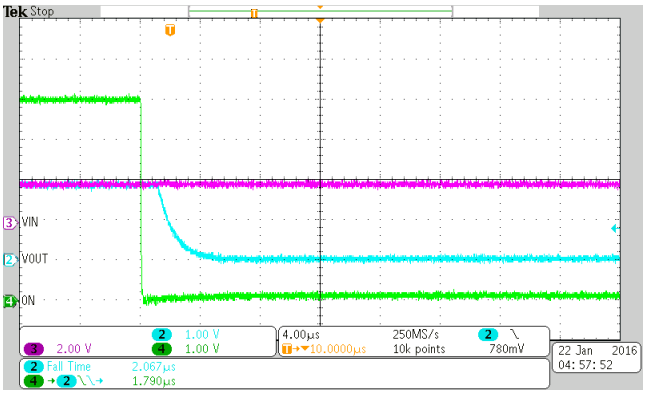
Copyright © 2016, Texas Instruments Incorporated

AC Characteristics (continued)



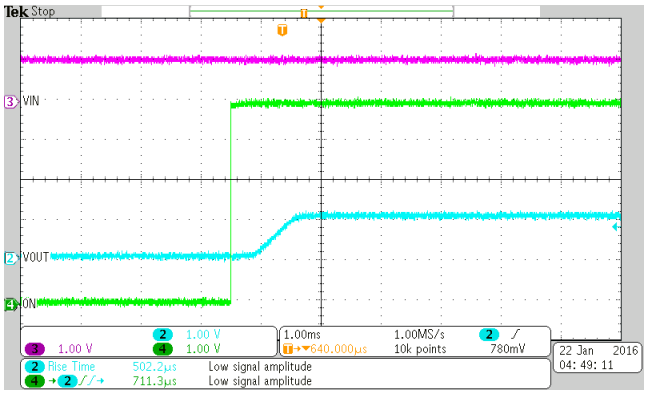
V_{IN} = 1.8 V C_{IN} = 1 µF C_L = 0.1 µF
R_L = 10 Ω CT = 1000 pF

Figure 17. t_R at V_{IN} = 1.8 V



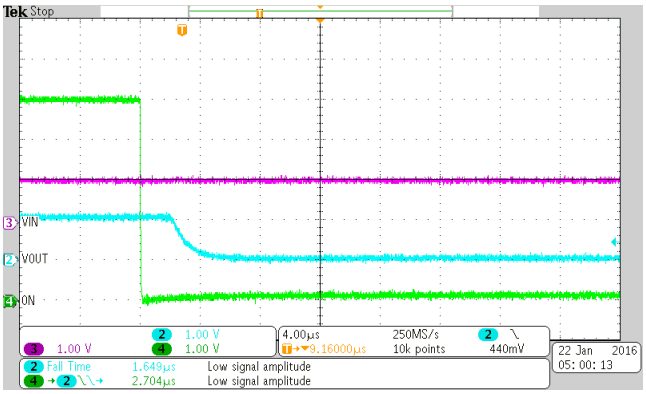
V_{IN} = 1.8 V C_{IN} = 1 µF C_L = 0.1 µF
R_L = 10 Ω QOD = Open

Figure 18. t_F at V_{IN} = 1.8 V



V_{IN} = 1.0 V C_{IN} = 1 µF C_L = 0.1 µF
R_L = 10 Ω CT = 1000 pF

Figure 19. t_R at V_{IN} = 1.0 V

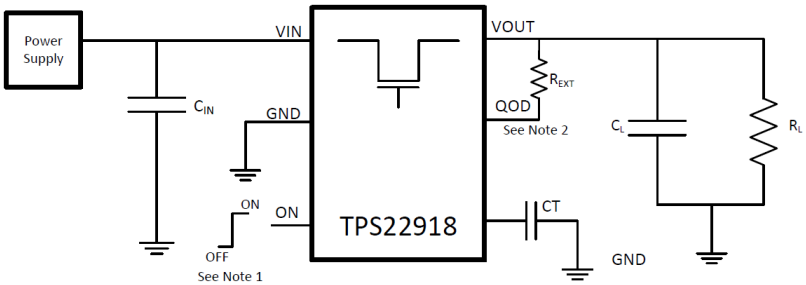


V_{IN} = 1.0 V C_{IN} = 1 µF C_L = 0.1 µF
R_L = 10 Ω QOD = Open

Figure 20. t_F at V_{IN} = 1.0 V

Copyright © 2016, Texas Instruments Incorporated

7 Parameter Measurement Information



(1) Rise and fall times of the control signal are 100 ns

(2) Turn-off times and fall times are dependent on the time constant at the load. For TPS22918, the internal pull-down resistance R_{PD} is enabled when the switch is disabled. The time constant is (R_{QOD} || R_L) × C_L.

Figure 21. Test Circuit

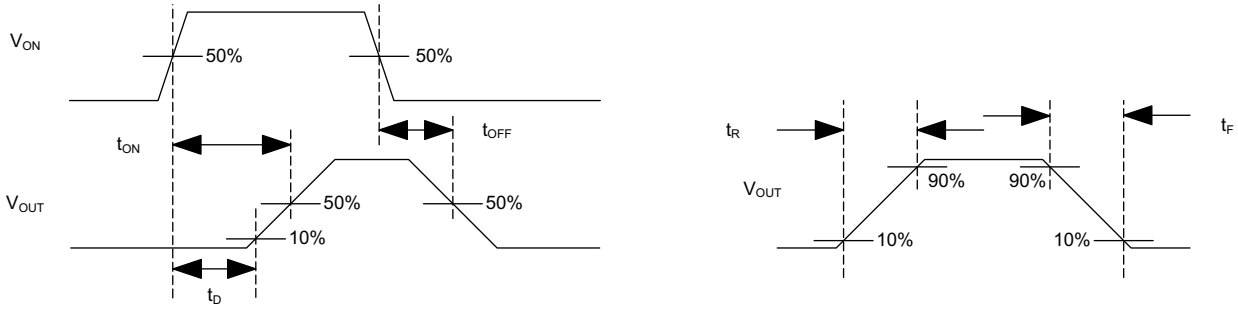


Figure 22. Timing Waveforms

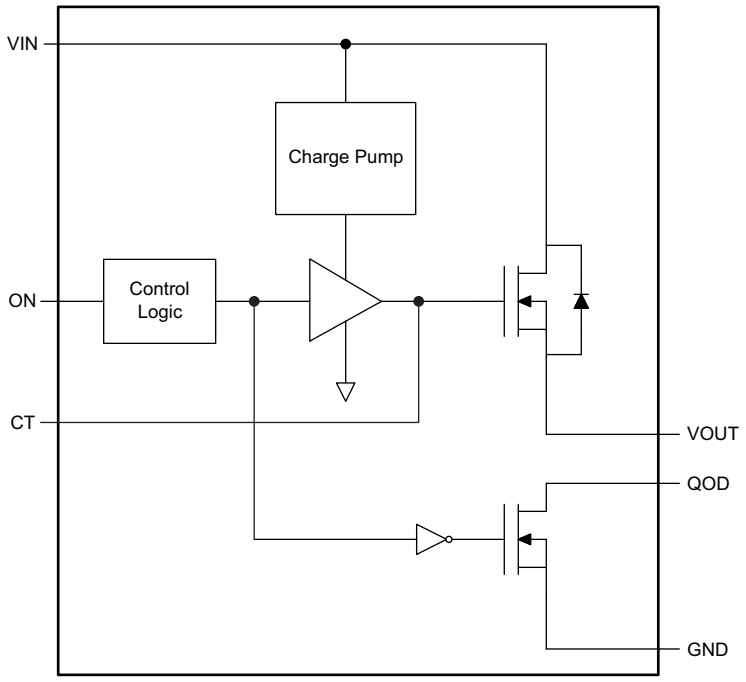
8 Detailed Description

8.1 Overview

The TPS22918 is a 5.5 V, 2 A load switch in a 6-pin SOT-23 package. To reduce voltage drop for low voltage and high current rails, the device implements a low resistance N-channel MOSFET which reduces the drop out voltage across the device.

The device has a configurable slew rate which helps reduce or eliminate power supply droop because of large inrush currents. Furthermore, the device features a QOD pin, which allows the configuration of the discharge rate of VOUT once the switch is disabled. During shutdown, the device has very low leakage currents, thereby reducing unnecessary leakages for downstream modules during standby. Integrated control logic, driver, charge pump, and output discharge FET eliminates the need for any external components which reduces solution size and bill of materials (BOM) count.

8.2 Functional Block Diagram



Copyright © 2016, Texas Instruments Incorporated

8.3 Feature Description

8.3.1 On and Off Control

The ON pin controls the state of the switch. ON is active high and has a low threshold, making it capable of interfacing with low-voltage signals. The ON pin is compatible with standard GPIO logic threshold. It can be used with any microcontroller with 1 V or higher GPIO voltage. This pin cannot be left floating and must be driven either high or low for proper functionality.

8.3.2 Quick Output Discharge (QOD)

The TPS22918 includes a QOD feature. The QOD pin can be configured in one of three ways:

- QOD pin shorted to VOUT pin. Using this method, the discharge rate after the switch becomes disabled is controlled with the value of the internal resistance R_{PD}. The value of this resistance is listed in the *Electrical Characteristics* table.
- QOD pin connected to VOUT pin using an external resistor R_{EXT}. After the switch becomes disabled, the discharge rate is controlled by the value of the total resistance of the QOD. To adjust the total QOD resistance, Equation 1 can be used:

  $$R_{QOD} = R_{PD} + R_{EXT} \quad (1)$$

  Where:
  - R_{QOD} = Total output discharge resistance
  - R_{PD} = Internal pulldown resistance
  - R_{EXT} = External resistance placed between the VOUT and QOD pin.
- QOD pin is unused and left floating. Using this method, there will be no quick output discharge functionality, and the output will remain floating after the switch is disabled.

The fall times of the device depend on many factors including the total resistance of the QOD, V_{IN}, and the output capacitance. When QOD is shorted to VOUT, the fall time will change over V_{IN} as the internal R_{PD} varies over V_{IN}. To calculate the approximate fall time of V_{OUT} for a given R_{QOD}, use Equation 2 and Table 1.

$$V_{CAP} = V_{IN} \times e^{-t/\tau} \quad (2)$$

Where:
- V_{CAP} = Voltage across the capacitor (V)
- t = Time since power supply removal (s)
- τ = Time constant equal to $R_{QOD} \times C_L$

The fall times' dependency on V_{IN} becomes minimal as the QOD value increases with additional external resistance. See Table 1 for QOD fall times.

Table 1. QOD Fall Times

V_{IN} (V)	(1) FALL TIME (µs) 90% - 10%, C_{IN} = 1 µF, I_{OUT} = 0 A , V_{ON} = 0 V					
	T_A = 25°C			T_A = 85°C		
	C_L = 1 µF	C_L = 10 µF	C_L = 100 µF	C_L = 1 µF	C_L = 10 µF	C_L = 100 µF
5.5	42	190	1880	40	210	2150
5	43	200	1905	45	220	2200
3.3	47	230	2150	50	260	2515
2.5	58	300	2790	60	345	3290
1.8	75	430	4165	80	490	4950
1.2	135	955	9910	135	1035	10980
1	230	1830	19625	210	1800	19270

(1) TYPICAL VALUES WITH QOD SHORTED TO VOUT

Copyright © 2016, Texas Instruments Incorporated

8.3.2.1 QOD when System Power is Removed

The adjustable QOD can be used to control the power down sequencing of a system even when the system power supply is removed. When the power is removed, the input capacitor discharges at V_{IN}. Past a certain V_{IN} level, the strength of the R_{PD} will be reduced. If there is still remaining charge on the output capacitor, this will result in longer fall times. For further information regarding this condition, refer to *Shutdown Sequencing During Unexpected System Power Loss*.

8.3.2.2 Internal QOD Considerations

Special considerations must be taken when using the internal R_{PD} by shorting the QOD pin to the VOUT pin. The internal R_{PD} is a pulldown resistance designed to quickly discharge a load after the switch has been disabled. Care must be used to ensure that excessive current does not flow through R_{PD} during discharge so that the maximum T_J of 125°C is not exceeded. When using only the internal R_{PD} to discharge a load, the total capacitive load must not exceed 200 µF. Otherwise, an external resistor, R_{EXT}, must be used to ensure the amount of current flowing through R_{PD} is properly limited and the maximum T_J is not exceeded. To ensure the device is not damaged, the remaining charge from C_L must decay naturally through the internal QOD resistance and should not be driven.

8.3.3 Adjustable Rise Time (CT)

A capacitor to GND on the CT pin sets the slew rate of V_{OUT}. The CT capacitor will charge up until shortly after the switch is turned on and V_{OUT} becomes stable. Once V_{OUT} become stable, the capactior will discharge to ground. An approximate formula for the relationship between CT and the slew rate is shown in Equation 3:

$$SR = 0.55\times CT + 30 \quad (3)$$

where

- SR = slew rate (in µs/V)
- CT = the capacitance value on the CT pin (in pF)
- The units for the constant 30 are µs/V. The units for the constant 0.52 are µs/(V × pF).

This equation accounts for 10% to 90% measurement on V_{OUT} and does not apply for CT = 0 pF. Use Table 2 to determine rise times for when CT = 0 pF.

Rise time can be calculated by multiplying the input voltage by the slew rate. Table 2 contains rise time values measured on a typical device.

Table 2. Rise Time Table

CT× (pF)	RISE TIME (µs) 10% - 90%, C_L = 0.1 µF, C_{IN} = 1 µF, R_L = 10 Ω (1)						
	VIN = 5 V	VIN = 3.3 V	VIN = 2.5 V	VIN = 1.8 V	VIN = 1.5 V	VIN = 1.2 V	VIN = 1.0 V
0	135	95	75	60	50	45	40
220	650	455	350	260	220	185	160
470	1260	850	655	480	415	340	300
1000	2540	1680	1300	960	810	660	560
2200	5435	3580	2760	2020	1715	1390	1220
4700	12050	7980	6135	4485	3790	3120	2735
10000	26550	17505	13460	9790	8320	6815	5950

(1) Typical values at 25°C with a 25 V X7R 10% ceramic capacitor on CT.

As the voltage across the capacitor approaches the capacitor rated voltage, the effective capacitance reduces. Depending on the dielectric material used, the voltage coefficient changes. See Table 3 for the recommended minimum voltage rating for the CT capacitor. If using V_{IN} = 1.2 V or 4 V, it is recommended to use the higher of the two CT Voltage ratings specified.

Copyright © 2016, Texas Instruments Incorporated

Table 3. Recommended CT Capacitor Voltage Rating

V_{IN} (V)	RECOMMENDED CT CAPACITOR VOLTAGE RATING (V)
1 V to 1.2 V	10
1.2 V to 4 V	16
4 V to 5.5 V	20

8.4 Device Functional Modes

Table 4 describes the connection of the VOUT pin depending on the state of the ON pin.

Table 4. VOUT Connection

ON	QOD CONFIGURATION	TPS22918 VOUT
L	QOD pin connected to VOUT with R_{EXT}	GND (via R_{EXT}+R_{PD})
L	QOD pin tied to VOUT directly	GND (via R_{PD})
L	QOD pin left open	Open
H	Any valid QOD configuration	VIN

Copyright © 2016, Texas Instruments Incorporated

9 Application and Implementation

NOTE

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

9.1 Application Information

This section highlights some of the design considerations when implementing this device in various applications. A PSPICE model for this device is also available in the product page of this device on www.ti.com (See the *器件支持* section for more information).

9.2 Typical Application

This typical application demonstrates how the TPS22918 can be used to power downstream modules.

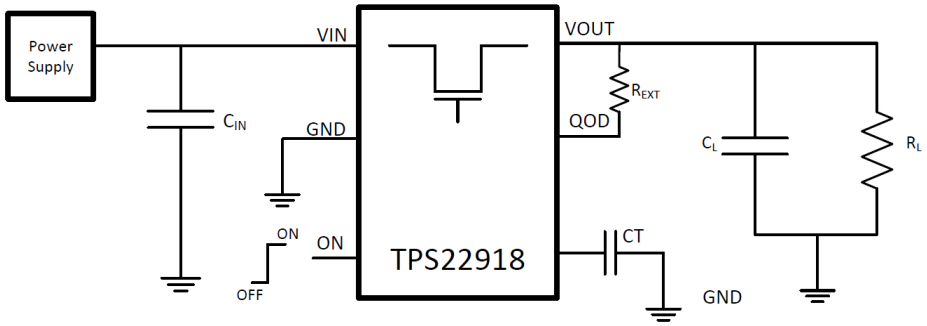


Figure 23. Typical Application Schematic

9.2.1 Design Requirements

For this design example, use the values listed in Table 5 as the design parameters:

Table 5. Design Parameters

DESIGN PARAMETER	EXAMPLE VALUE
V_{IN}	5 V
Load Current	2 A
C_L	22 µF
Desired Fall Time	4 ms
Maximum Acceptable Inrush Current	400 mA

Copyright © 2016, Texas Instruments Incorporated

9.2.2 Detailed Design Procedure

9.2.2.1 Input Capacitor (C_{IN})

To limit the voltage drop on the input supply caused by transient in-rush currents when the switch turns on into a discharged load capacitor or short-circuit, a capacitor needs to be placed between VIN and GND. A 1 µF ceramic capacitor, C_{IN}, placed close to the pins, is usually sufficient. Higher values of C_{IN} can be used to further reduce the voltage drop during high-current application. When switching heavy loads, it is recommended to have an input capacitor about 10 times higher than the output capacitor to avoid excessive voltage drop.

9.2.2.2 Output Capacitor (C_L) (Optional)

Becuase of the integrated body diode in the MOSFET, a C_{IN} greater than C_L is highly recommended. A C_L greater than C_{IN} can cause V_{OUT} to exceed V_{IN} when the system supply is removed. This could result in current flow through the body diode from VOUT to VIN. A C_{IN} to C_L ratio of 10 to 1 is recommended for minimizing V_{IN} dip caused by inrush currents during startup.

9.2.2.3 Shutdown Sequencing During Unexpected System Power Loss

Microcontrollers and processors often have a specific shutdown sequence in which power needs to be removed. Using the adjustable Quick Output Discharge function of the TPS22918, adding a load switch to each power rail can be used to manage the power down sequencing in the event of an unexpected system power loss (i.e. battery removal). To determine the QOD values for each load switch, first confirm the power down order of the device you wish to power sequence. Be sure to check if there are voltage or timing margins that must be maintained during power down. Next, consult QOD Fall Time Table in the *Quick Output Discharge (QOD)* feature description to determine appropriate C_{OUT} and R_{QOD} values for each power rail's load switch so that the load switches' fall times correspond to the order in which they need to be powered down. In the above example, we would like this power rail's fall time to be 4 ms. Using Equation 2, to determine the appropriate R_{QOD} to achieve our desired fall time.

Because fall times are measured from 90% of V_{OUT} to 10% of V_{OUT}, the equation becomes:

$$.5\ V = 4.5\ V \times e^{-(4\ ms)\ /\ (R \times (22\ \mu F))} \quad (4)$$

$$R_{QOD} = 83.333\ \Omega \quad (5)$$

Refer to Figure 7, R_{PD} at V_{IN} = 5 V is approximately 25 Ω. Using Equation 1, the required external QOD resistance can be calculated:

$$83.333\ \Omega = 25\ \Omega + R_{EXT} \quad (6)$$

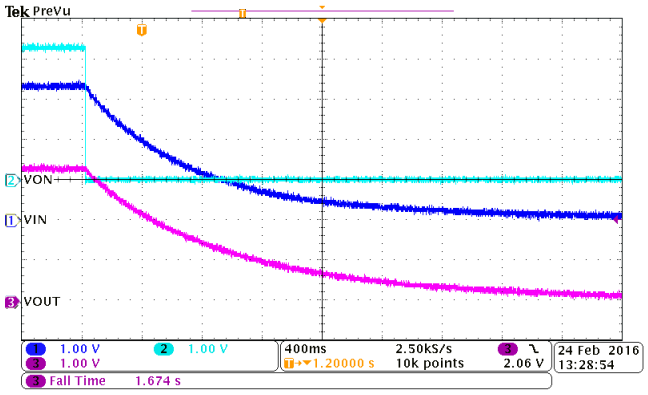
$$R_{EXT} = 58.333\ \Omega \quad (7)$$

Figure 24 through Figure 29 are scope shots demonstrating an example of the QOD functionality when power is removed from the device (both ON and VIN are disconnected simultaneously). The input voltage is decaying in all scope shots below.

- Initial V_{IN} = 3.3 V
- QOD = Open, 500 Ω, or shorted to VOUT
- C_L = 1 µF, 10 µF
- V_{OUT} is left floating

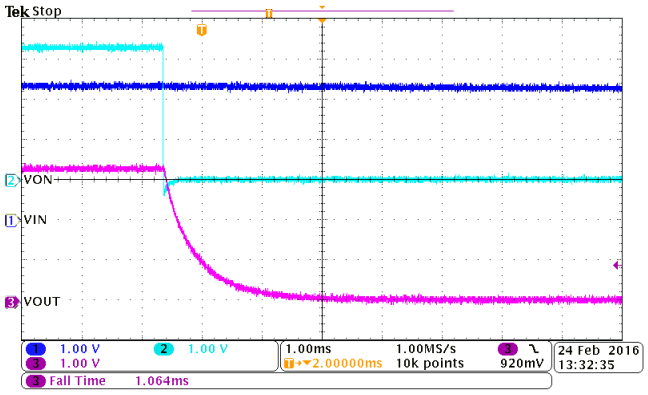
NOTE: V_{IN} may appear constant in some figures. This is because the time scale of the scope shot is too small to show the decay of C_{IN}.

Copyright © 2016, Texas Instruments Incorporated



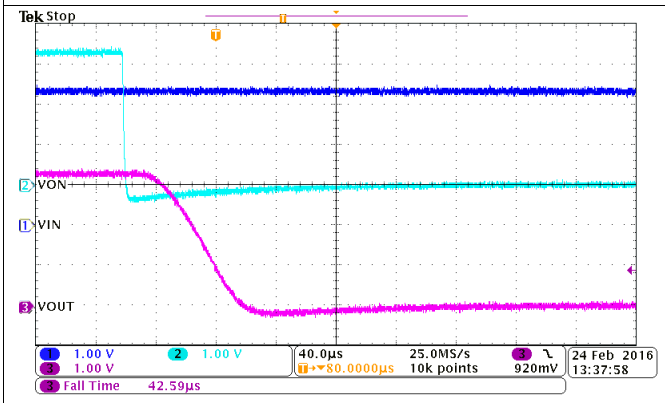
V_{IN} = 3.3 V C_{IN} = 1 µF C_L = 1 µF
QOD = Open

Figure 24. t_F at V_{IN} = 3.3 V



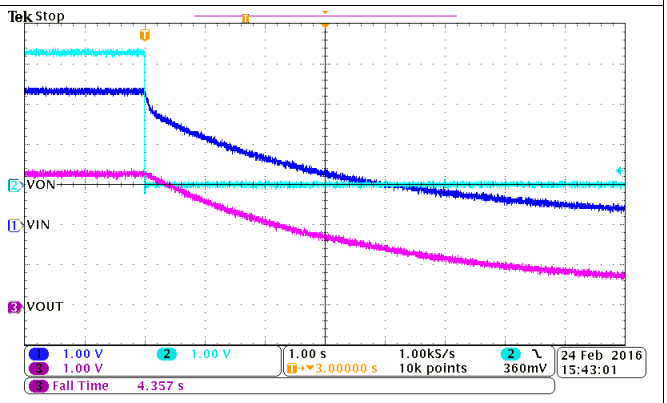
V_{IN} = 3.3 V C_{IN} = 1 µF C_L = 1 µF
QOD = 500 Ω

Figure 25. t_F at V_{IN} = 3.3 V



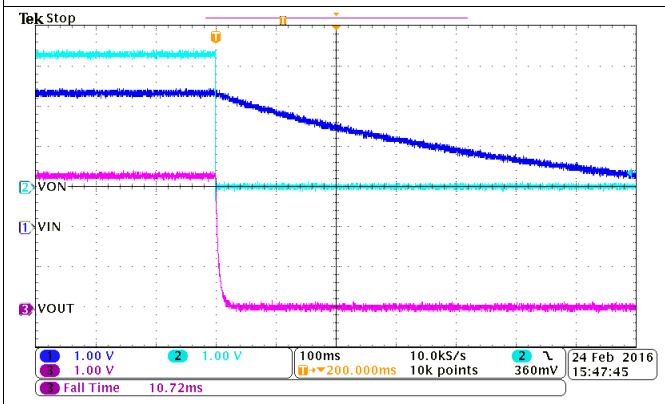
V_{IN} = 3.3 V C_{IN} = 1 µF C_L = 1 µF
QOD = V_{OUT}

Figure 26. t_F at V_{IN} = 3.3 V



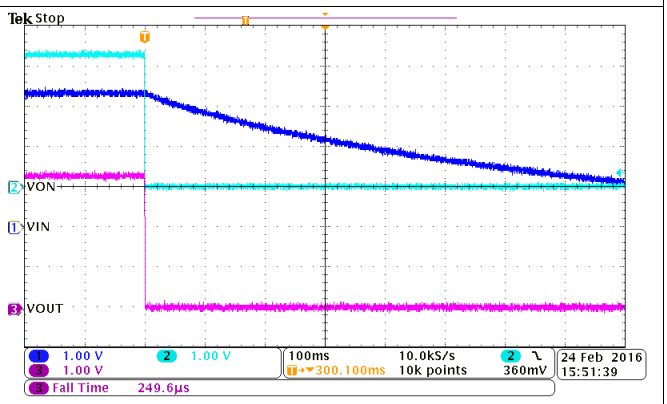
V_{IN} = 3.3 V C_{IN} = 1 µF C_L = 10 µF
QOD = Open

Figure 27. t_F at V_{IN} = 3.3 V



V_{IN} = 3.3 V C_{IN} = 1 µF C_L = 10 µF
QOD = 500 Ω

Figure 28. t_F at V_{IN} = 3.3 V



V_{IN} = 3.3 V C_{IN} = 1 µF C_L = 10 µF
QOD = VOUT

Figure 29. t_F at V_{IN} = 3.3 V

Copyright © 2016, Texas Instruments Incorporated

9.2.2.4 VIN to VOUT Voltage Drop

The VIN to VOUT voltage drop in the device is determined by the R_{ON} of the device and the load current. The R_{ON} of the device depends upon the VIN conditions of the device. Refer to the R_{ON} specification of the device in the *Electrical Characteristics* table of this data sheet. When the R_{ON} of the device is determined based upon the VIN conditions, use 公式 8 to calculate the VIN to VOUT voltage drop:

$$\Delta V = I_{LOAD} \times R_{ON}$$

where

- ΔV = voltage drop from VIN to VOUT
- I_{LOAD} = load current
- R_{ON} = On-resistance of the device for a specific V_{IN}

An appropriate I_{LOAD} must be chosen such that the I_{MAX} specification of the device is not violated. (8)

9.2.2.5 Inrush Current

Use 公式 9 to determine how much inrush current will be caused by the C_L capacitor:

$$I_{INRUSH} = C_L \times \frac{dV_{OUT}}{dt}$$

where

- I_{INRUSH} = amount of inrush caused by C_L
- C_L = capacitance on VOUT
- dt = Output Voltage rise time during the ramp up of VOUT when the device is enabled
- dV_{OUT} = change in V_{OUT} during the ramp up of VOUT when the device is enabled (9)

The appropriate rise time can be calculated using the design requirements and the inrush current equation. As we are calculating the rise time (measured from 10% to 90% of V_{OUT}), we will account for this in our dV_{OUT} parameter (80% of V_{OUT} = 4 V).

$$400\ mA = 22\ \mu F \times 4\ V/dt \quad (10)$$

$$dt = 220\ \mu s \quad (11)$$

To ensure an inrush current of less than 400 mA, choose a CT value that will yield a rise time of more than 220 µs. Consulting Table 2 at V_{IN} = 5 V, CT = 220 µF will provide a typical rise time of 650 µs. Inputting this rise time and voltage into 公式 9, yields:

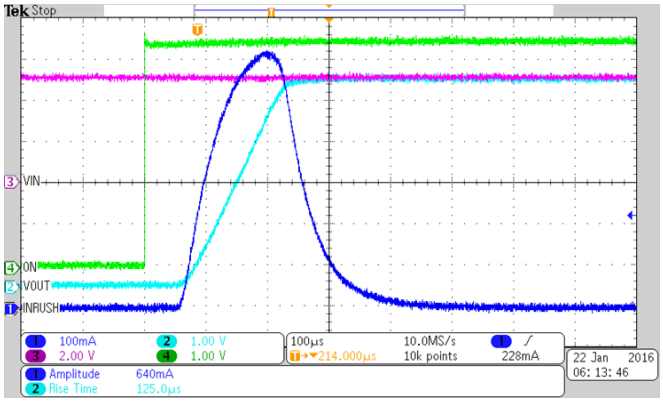
$$I_{Inrush} = 22\ \mu F \times 4\ V / 650\ \mu s \quad (12)$$

$$I_{Inrush} = 135\ mA \quad (13)$$

This inrush current can be seen in the Application Curves below. An appropriate C_L value should be placed on VOUT such that the I_{MAX} and I_{PLS} specifications of the device are not violated.

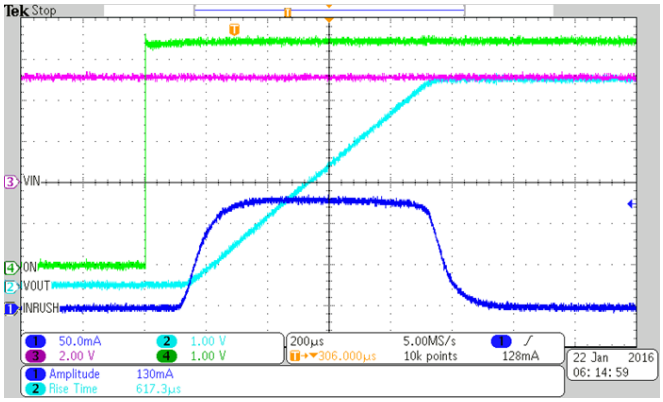
版权 © 2016, Texas Instruments Incorporated

9.2.3 Application Curves



V_{IN} = 5 V C_L = 22 µF CT = 0 µF

图 30. TPS22918 Inrush Current



V_{IN} = 5 V C_L = 22 µF CT = 220 µF

图 31. TPS22918 Inrush Current

10 Power Supply Recommendations

The device is designed to operate from a VIN range of 1 V to 5.5 V. This supply must be well regulated and placed as close to the device terminal as possible with the recommended 1-µF bypass capacitor. If the supply is located more than a few inches from the device terminals, additional bulk capacitance may be required in addition to the ceramic bypass capacitors. If additional bulk capacitance is required, an electrolytic, tantalum, or ceramic capacitor of 1 µF may be sufficient.

The TPS22918 operates regardless of power sequencing order. The order in which voltages are applied to V_{IN} and ON will not damage the device as long as the voltages do not exceed the absolute maximum operating conditions. If voltage is applied to ON before V_{IN}, the slew rate of V_{OUT} will not be controlled.

11 Layout

11.1 Layout Guidelines

VIN and VOUT traces should be as short and wide as possible to accommodate for high current.

The VIN pin should be bypassed to ground with low ESR ceramic bypass capacitors. The typical recommended bypass capacitance is 1-µF ceramic with X5R or X7R dielectric. This capacitor should be placed as close to the device pins as possible.

版权 © 2016, Texas Instruments Incorporated

11.2 Layout Example

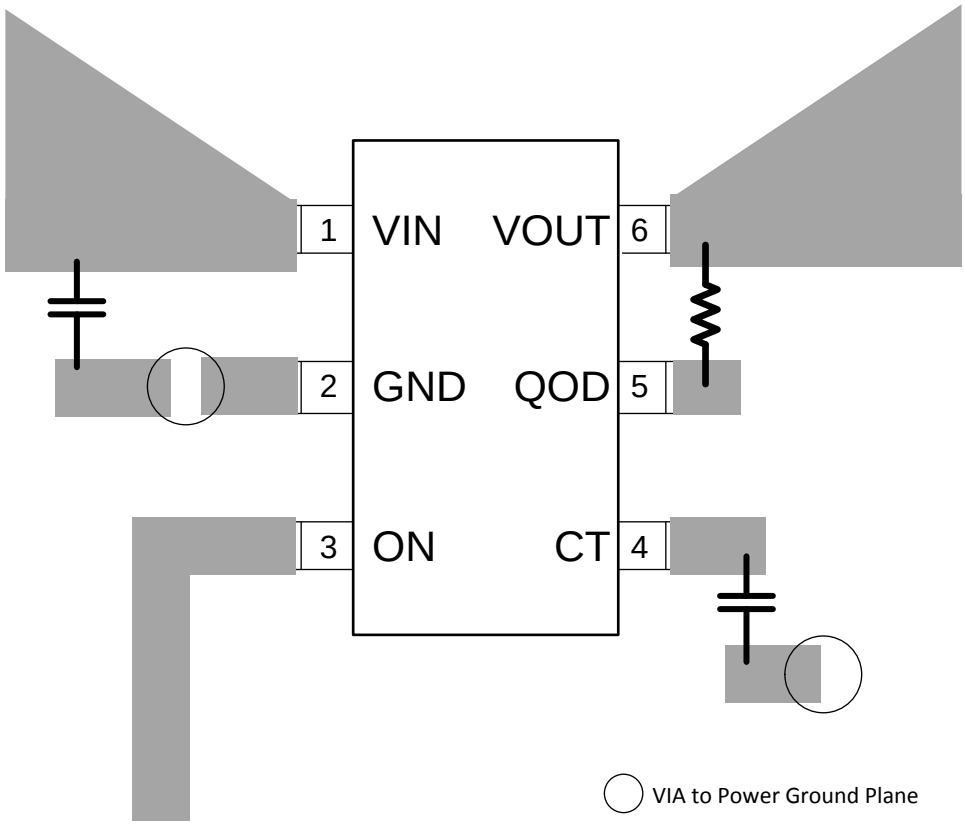


图 32. Recommended Board Layout

11.3 Thermal Considerations

For best performance, all traces should be as short as possible. To be most effective, the input and output capacitors should be placed close to the device to minimize the effects that parasitic trace inductances may have on normal and short-circuit operation. Using wide traces for VIN, VOUT, and GND helps minimize the parasitic electrical effects along with minimizing the case to ambient thermal impedance.

The maximum IC junction temperature should be restricted to 125°C under normal operating conditions. To calculate the maximum allowable dissipation, $P_{D(max)}$ for a given output current and ambient temperature, use 公式 14:

$$P_{D(MAX)} = \frac{T_{J(MAX)} - T_A}{\theta_{JA}} \quad (14)$$

where

- $P_{D(MAX)}$ = maximum allowable power dissipation
- $T_{J(MAX)}$ = maximum allowable junction temperature (125°C for the TPS22918)
- T_A = ambient temperature of the device
- θ_{JA} = junction to air thermal impedance. Refer to the *Thermal Information* table. This parameter is highly dependent upon board layout.

12 器件和文档支持

12.1 器件支持

12.1.1 开发支持

关于 TPS22918 PSpice 瞬态模型，请参见 SLVMBI6。

12.2 文档支持

12.2.1 相关文档

相关文档如下：

《TPS22918 5.5V、2A、导通电阻为 50mΩ 的负载开关评估模块》，SLVUAP0。

12.3 社区资源

The following links connect to TI community resources. Linked contents are provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

TI E2E™ Online Community ***TI's Engineer-to-Engineer (E2E) Community.*** Created to foster collaboration among engineers. At e2e.ti.com, you can ask questions, share knowledge, explore ideas and help solve problems with fellow engineers.

Design Support ***TI's Design Support*** Quickly find helpful E2E forums along with design support tools and contact information for technical support.

12.4 商标

E2E is a trademark of Texas Instruments.
All other trademarks are the property of their respective owners.

12.5 静电放电警告

这些装置包含有限的内置 ESD 保护。 存储或装卸时，应将导线一起截短或将装置放置于导电泡棉中，以防止 MOS 门极遭受静电损伤。

12.6 Glossary

SLYZ022 — *TI Glossary*.

This glossary lists and explains terms, acronyms, and definitions.

13 机械、封装和可订购信息

以下页中包括机械、封装和可订购信息。这些信息是针对指定器件可提供的最新数据。这些数据会在无通知且不对本文档进行修订的情况下发生改变。欲获得该数据表的浏览器版本，请查阅左侧的导航栏。

版权 © 2016, Texas Instruments Incorporated

PACKAGING INFORMATION

Orderable part number	Status (1)	Material type (2)	Package | Pins	Package qty | Carrier	RoHS (3)	Lead finish/ Ball material (4)	MSL rating/ Peak reflow (5)	Op temp (°C)	Part marking (6)
TPS22918DBVR	Active	Production	SOT-23 (DBV) | 6	3000 | LARGE T&R	Yes	NIPDAU | SN	Level-2-260C-1 YEAR	-40 to 105	13MW
TPS22918DBVR.A	Active	Production	SOT-23 (DBV) | 6	3000 | LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 105	13MW
TPS22918DBVT	Active	Production	SOT-23 (DBV) | 6	250 | SMALL T&R	Yes	NIPDAU | SN	Level-2-260C-1 YEAR	-40 to 105	13MW
TPS22918DBVT.A	Active	Production	SOT-23 (DBV) | 6	250 | SMALL T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 105	13MW
TPS22918DBVTG4.A	Active	Production	SOT-23 (DBV) | 6	250 | SMALL T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 105	13MW

(1) **Status:** For more details on status, see our product life cycle.

(2) **Material type:** When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

(3) **RoHS values:** Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

(4) **Lead finish/Ball material:** Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

(5) **MSL rating/Peak reflow:** The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

(6) **Part marking:** There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

OTHER QUALIFIED VERSIONS OF TPS22918 :

- Automotive : TPS22918-Q1

NOTE: Qualified Version Definitions:

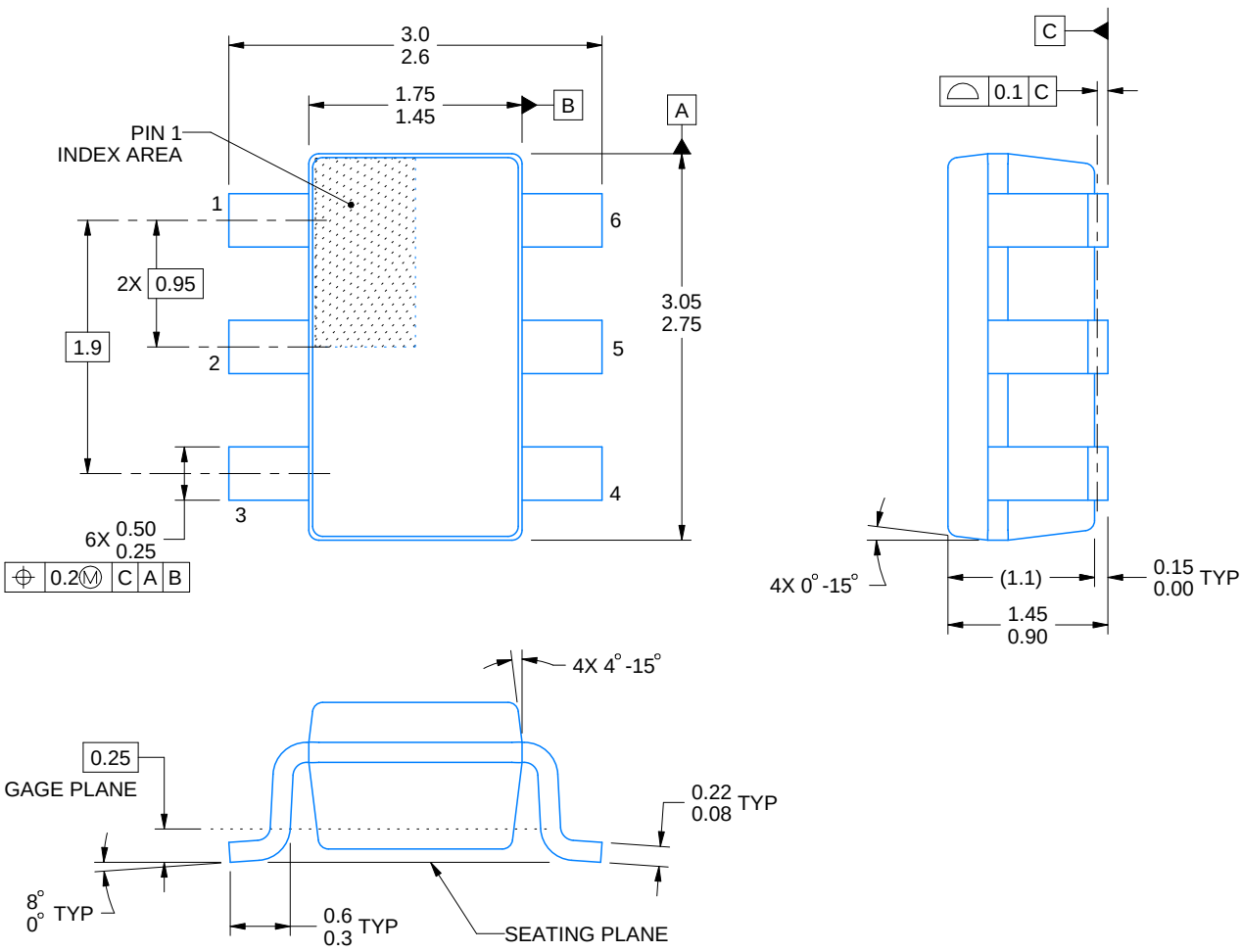
- Automotive - Q100 devices qualified for high-reliability automotive applications targeting zero defects

PACKAGE OUTLINE

DBV0006A

SOT-23 - 1.45 mm max height

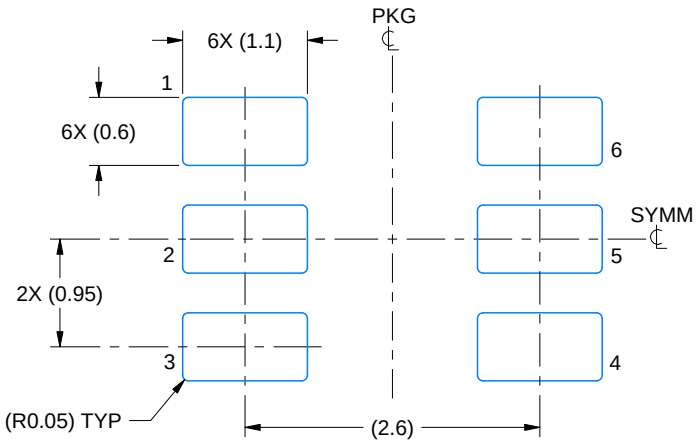
SMALL OUTLINE TRANSISTOR



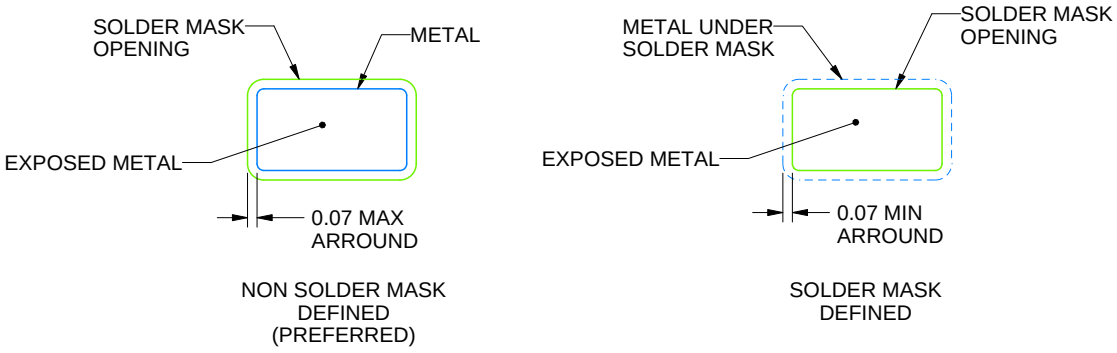
4214840/G 08/2024

NOTES:

1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. Body dimensions do not include mold flash or protrusion. Mold flash and protrusion shall not exceed 0.25 per side.
4. Leads 1,2,3 may be wider than leads 4,5,6 for package orientation.
5. Refernce JEDEC MO-178.



LAND PATTERN EXAMPLE
EXPOSED METAL SHOWN
SCALE:15X

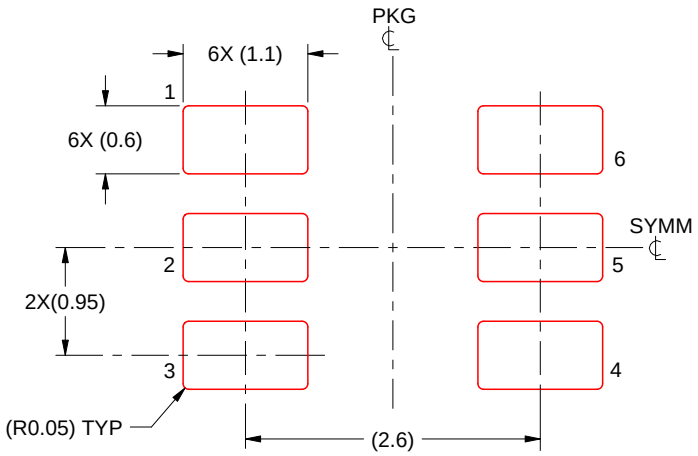


SOLDER MASK DETAILS

4214840/G 08/2024

NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.
7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SOLDER PASTE EXAMPLE
BASED ON 0.125 mm THICK STENCIL
SCALE:15X

4214840/G 08/2024

NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
9. Board assembly site may have different recommendations for stencil design.

重要通知和免责声明

TI“按原样”提供技术和可靠性数据（包括数据表）、设计资源（包括参考设计）、应用或其他设计建议、网络工具、安全信息和其他资源，不保证没有瑕疵且不做出任何明示或暗示的担保，包括但不限于对适销性、某特定用途方面的适用性或不侵犯任何第三方知识产权的暗示担保。

这些资源可供使用 TI 产品进行设计的熟练开发人员使用。您将自行承担以下全部责任：(1) 针对您的应用选择合适的 TI 产品，(2) 设计、验证并测试您的应用，(3) 确保您的应用满足相应标准以及任何其他功能安全、信息安全、监管或其他要求。

这些资源如有变更，恕不另行通知。TI 授权您仅可将这些资源用于研发本资源所述的 TI 产品的相关应用。 严禁以其他方式对这些资源进行复制或展示。您无权使用任何其他 TI 知识产权或任何第三方知识产权。您应全额赔偿因在这些资源的使用中对 TI 及其代表造成的任何索赔、损害、成本、损失和债务，TI 对此概不负责。

TI 提供的产品受 TI 的销售条款或 ti.com 上其他适用条款/TI 产品随附的其他适用条款的约束。TI 提供这些资源并不会扩展或以其他方式更改 TI 针对 TI 产品发布的适用的担保或担保免责声明。

TI 反对并拒绝您可能提出的任何其他或不同的条款。

邮寄地址：Texas Instruments, Post Office Box 655303, Dallas, Texas 75265
版权所有 © 2025，德州仪器 (TI) 公司